Dual Beam PFIB/SEM Demonstration

RSC Host: Dr. Nicholas “Nick” Rudawski

Presenter: Dr. Nicholas “Nick” Rudawski

Affiliation: UF Research Service Centers

Time: 1:00 PM – 1:30 PM EST

Zoom: Click here to join!

Description

Join Nick as he virtually demonstrates some of the capabilities of the newly acquired dual beam PFIB/SEM housed at the RSCs. Multiple capabilities of the instrument will be demonstrated including:

- In-situ electron and ion beam-assisted metal deposition
- Site-specific ion beam milling and cross-sectional SEM imaging
- In-situ micromanipulation for lifting out TEM lamellas

More about the presenter

Presenter Bio: Nicholas G. Rudawski received his B.S.E. degree in Materials Science and Engineering from the University of Michigan in 2005 and his Ph.D. degree in Materials Science and Engineering from the University of Florida in 2008. He joined the Research Service Centers in August of 2012 as service/teaching faculty, where he oversees training, operation, and maintenance of the transmission electron microscopes and dual beam FIB/SEM systems. He has authored or coauthored approximately 50 electron microscopy-related peer-reviewed publications since 2003.

FEI Helios G4 PFIB CXe Dual Beam FIB/SEM: https://rsc.aux.eng.ufl.edu/ccb/resource.asp?id=142